

GROUP

[illegible]

		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							YES	NO
Ja	A1	H05-45423	02/23/1993	Japan				✓
TN	A2	H10-4128	01/06/1998	Japan				✓
Ja	A3	H05-74911	03/26/1993	Japan				✓
Ja	A4	60-165562	08/28/1985	Japan				✓
TN	A5	10-253710	09/25/1998	Japan				✓

7a		A6	B. Kruseman et al., "Transient Current Testing of 0.25 μ m CMOS Devices", ITC Int'l. Test Conf., September 28-30, 1999, pages 47-56

DATE CONSIDERED

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Masahiro ISHIDA et al. 0318 PCT/PTO 03 DEC 2001

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U.S. PATENT DOCUMENTS

*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE

FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							YES	NO
<i>pn</i>	C1	2001-91568	04/06/2001	Japan				✓

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

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